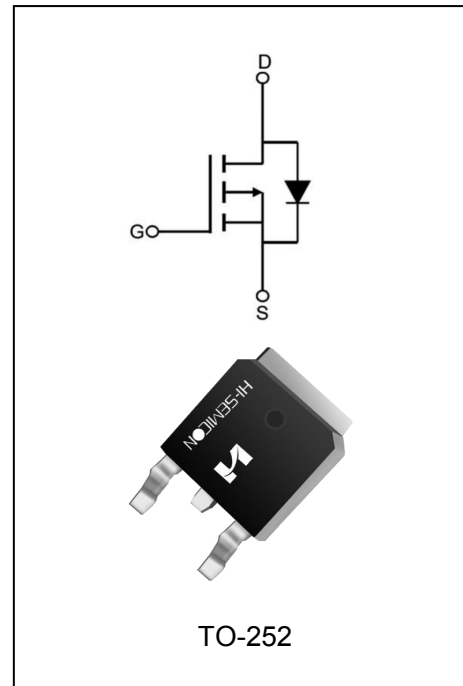


-40A, -40V P-CHANNEL MOSFET**GENERAL DESCRIPTION**

The SFD4004PT uses advanced trench technology and design to provide excellent $R_{DS(on)}$ with low gate charge. It can be used in a wide variety of applications. Such as: PWM Applications, Power Management

FEATURES

- ◆ $R_{DS(on)} = 11m\Omega(Typ) @ V_{GS} = -10V, I_D = -10A$
- ◆ $R_{DS(on)} = 14m\Omega(Typ) @ V_{GS} = -4.5V, I_D = -10A$
- ◆ $V_{DS} = -40V, I_D = -40A$
- ◆ Advance Trench Technology
- ◆ Fast Switching and High efficiency
- ◆ Lead Free and Green Devices Available: RoHS Compliant

**ORDERING INFORMATION**

Part No.	Package	Marking	Material	Packing
SFD4004PT	TO-252-2L	SFD4004PT	Pb Free	Reel

ABSOLUTE MAXIMUM RATINGS ($T_C=25^{\circ}\text{C}$ unless otherwise noted)

Characteristics		Symbol	Ratings	Unit
Drain-Source Voltage		V_{DS}	-40	V
Gate-Source Voltage		V_{GS}	± 20	V
Drain Current	$T_C = 25^{\circ}\text{C}$	I_D	-40	A
	$T_C = 100^{\circ}\text{C}$		-28	
Drain Current Pulsed(Note 1)		I_{DM}	-160	A
Power Dissipation($T_C=25^{\circ}\text{C}$)		P_D	80	W
Single Pulsed Avalanche Energy (Note 2)		E_{AS}	523	mJ
Operation Junction Temperature Range		T_J	-55~+175	$^{\circ}\text{C}$
Storage Temperature Range		T_{stg}	-55~+175	$^{\circ}\text{C}$

THERMAL CHARACTERISTICS

Characteristics	Symbol	MAX	Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	2.6	$^{\circ}\text{C/W}$
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	62.5	$^{\circ}\text{C/W}$

ELECTRICAL CHARACTERISTICS

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Off Characteristics						
Drain -Source Breakdown Voltage	B _{VDSS}	V _{GS} =0V, I _D =-250μA	-40	--	--	V
Drain-Source Leakage Current	I _{DSS}	V _{DS} =-40V, V _{GS} =0V	--	--	100	nA
Gate-Source Leakage Current	I _{GSS}	V _{GS} =20V, V _{DS} =0V	--	--	100	nA
Gate-Source Leakage Current	I _{GSS}	V _{GS} =-20V, V _{DS} =0V	--	--	-100	nA
On Characteristics						
Gate Threshold Voltage	V _{GS(th)}	V _{GS} = V _{DS} , I _D =-250μA	-1.0	--	-2.5	V
Static Drain- Source On State Resistance(Note 3)	R _{DS(on)}	V _{GS} =-10V, I _D =-10A	--	11	13	mΩ
		V _{GS} =-4.5V, I _D =-10A	--	14	17	
Forward Transconductance	g _{FS}	V _{GS} =-5.0V, I _D =-12A	--	31	--	S
Dynamic Characteristics						
Input Capacitance	C _{iSS}	V _{DS} =-20V V _{GS} =0V f=1.0MHZ	--	2523	--	pF
Output Capacitance	C _{oSS}		--	320	--	
Reverse Transfer Capacitance	C _{rSS}		--	305	--	
Total Gate Charge	Q _g	V _{DS} =-20V I _D =-12A V _{GS} =-10V (Note 3.4)	--	65	--	nC
Gate-Source Charge	Q _{gs}		--	12	--	
Gate-Drain Charge	Q _{gd}		--	13	--	
Switching Characteristics						
Turn-on Delay Time	t _{d(on)}	V _{DD} =-20V I _D =-12A V _{GS} =-10V R _G =2.5Ω (Note 3.4)	--	11	--	ns
Turn-on Rise Time	t _r		--	16	--	
Turn-off Delay Time	t _{d(off)}		--	35	--	

Turn-off Fall Time	t_f	$V_{DD}=-20V$ $I_D=-12A$ $V_{GS}=-12V$ $R_G=2.5\Omega$	--	25	--	ns
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SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

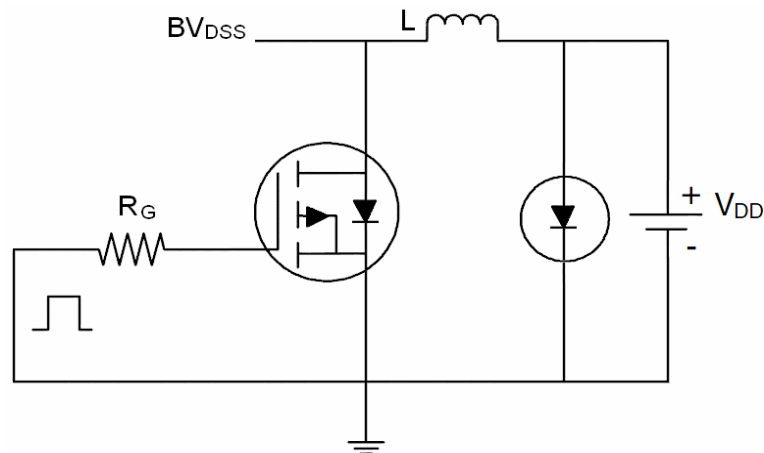
Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Continuous Source Current	I_S	Integral Reverse P-N Junction Diode in the MOSFET	--	--	-40	A
Pulsed Source Current	I_{SM}		--	--	-160	
Diode Forward Voltage	V_{SD}	$I_S=-12A, V_{GS}=0V$	--	--	1.2	V

Notes:

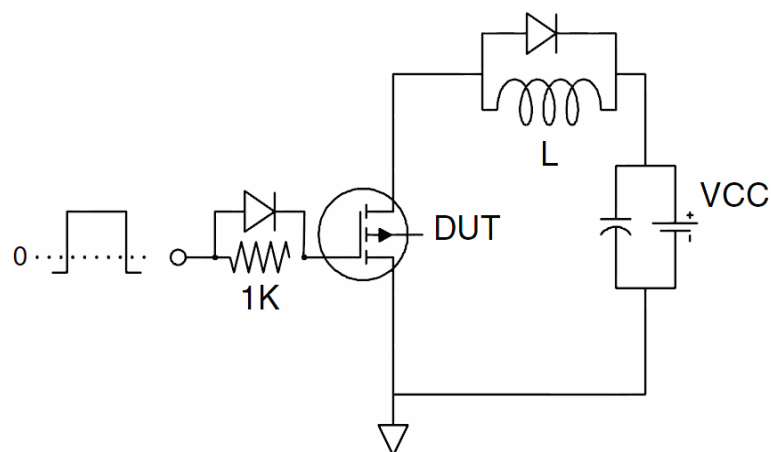
1. Pulse width limited by maximum junction temperature
2. $L=0.5mH$, $V_{DD}=-20V$, $V_G=-10V$, $R_G=25\Omega$, starting $T_J=25^\circ C$
3. Pulse Test: Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$
4. Essentially independent of operating temperature

TYPICAL TEST CIRCUIT

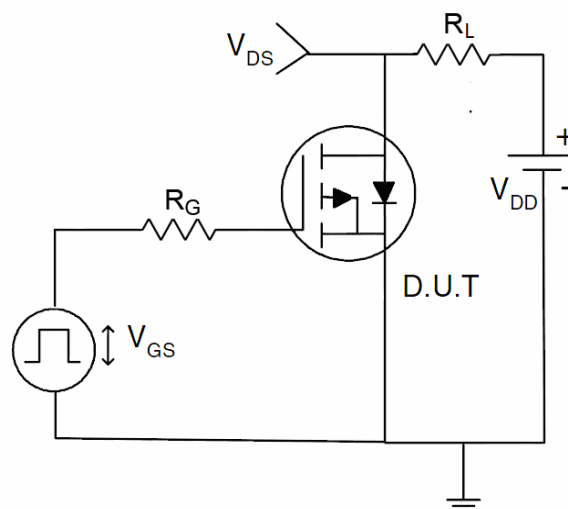
1) E_{AS} Test Circuit



2) Gate Charge Test Circuit



3) Switch Time Test Circuit



TYPICAL CHARACTERISTICS

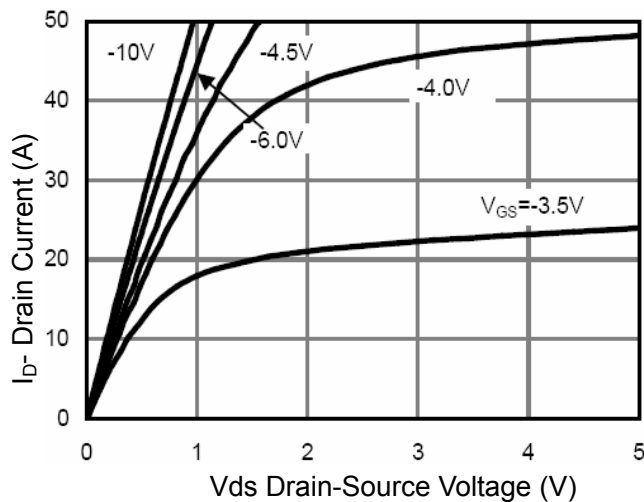


Figure 1 Output Characteristics

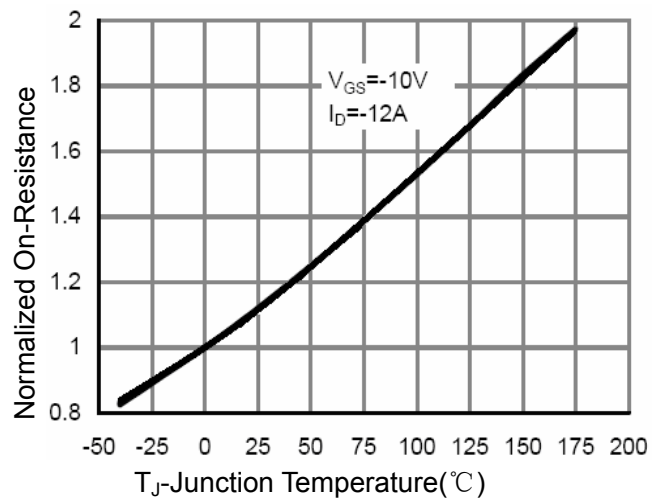


Figure 4 R_{dson} -Junction Temperature

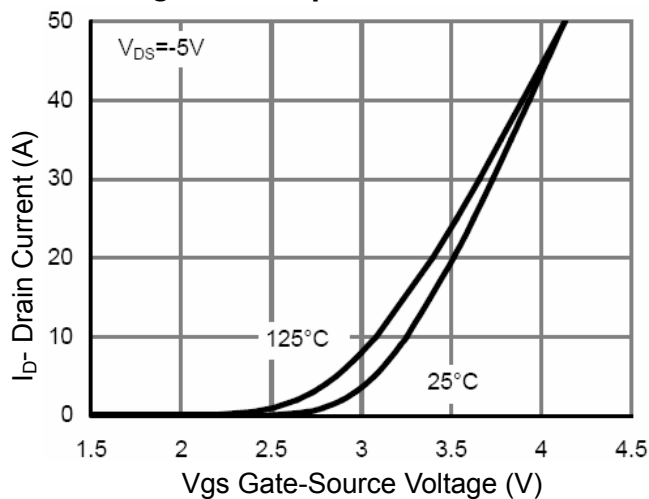


Figure 2 Transfer Characteristics

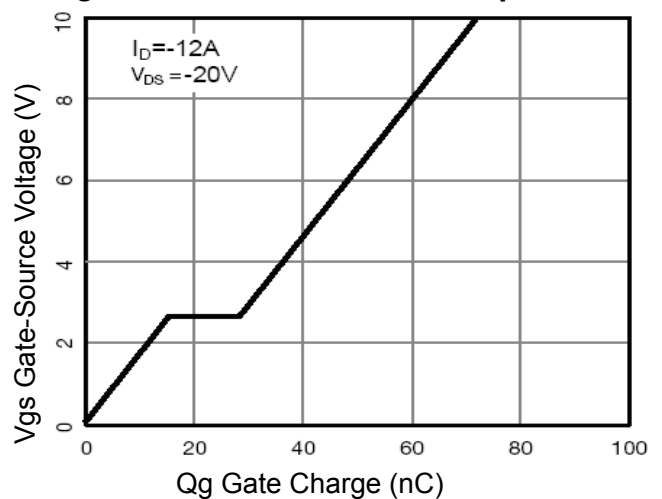


Figure 5 Gate Charge

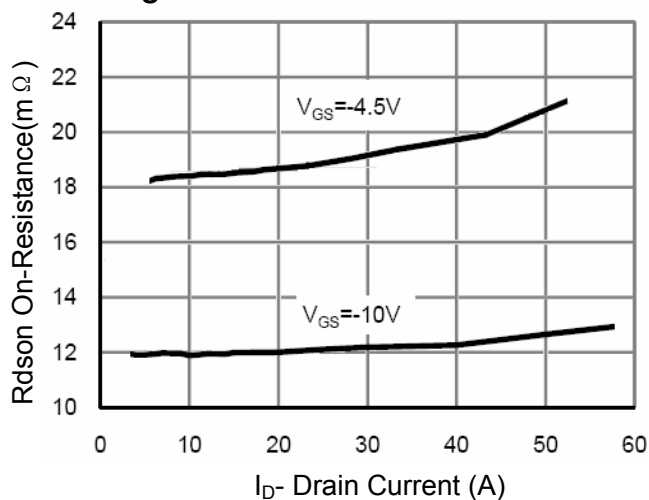


Figure 3 R_{dson} - Drain Current

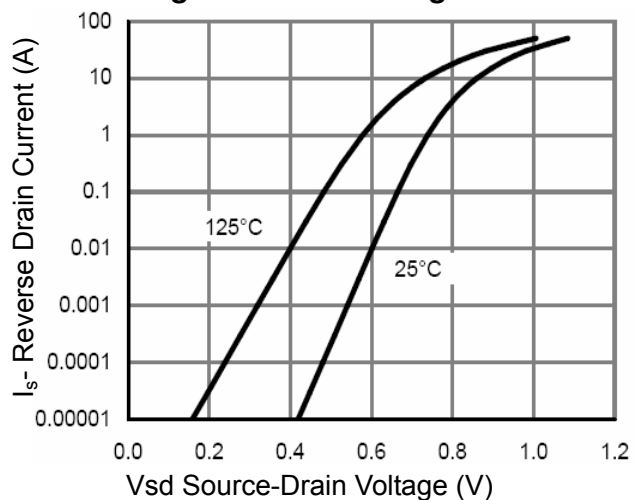


Figure 6 Source- Drain Diode Forward

TYPICAL CHARACTERISTICS

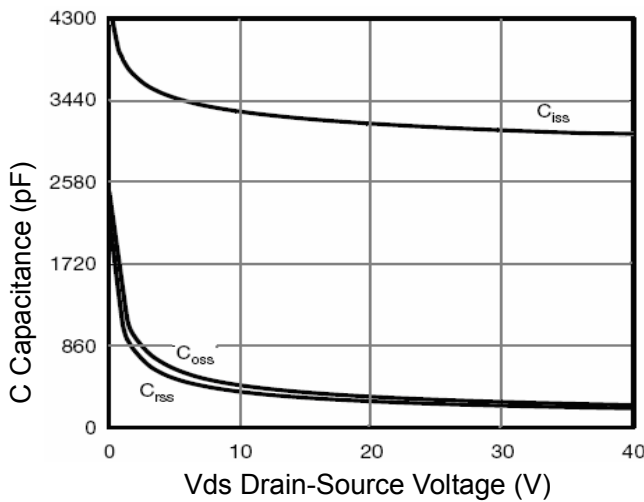


Figure 7 Capacitance vs Vds

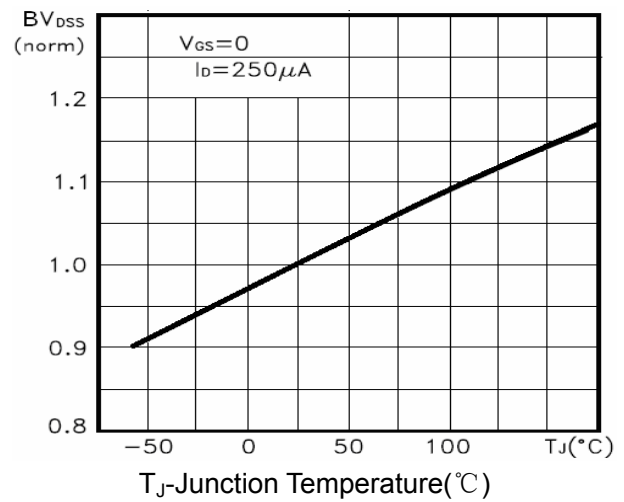


Figure 9 BV_{DSS} vs Junction Temperature

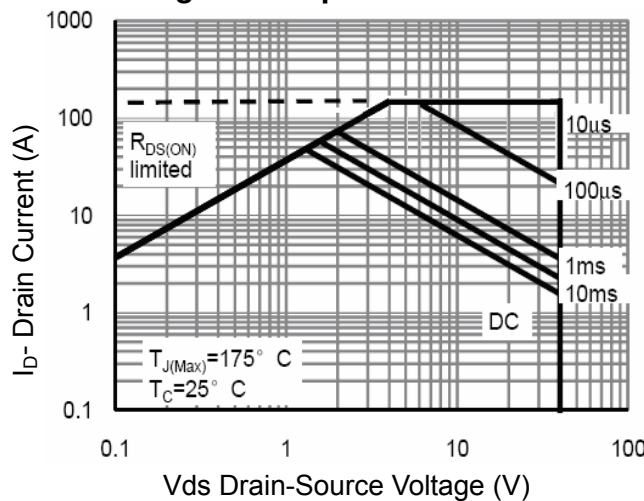


Figure 8 Safe Operation Area

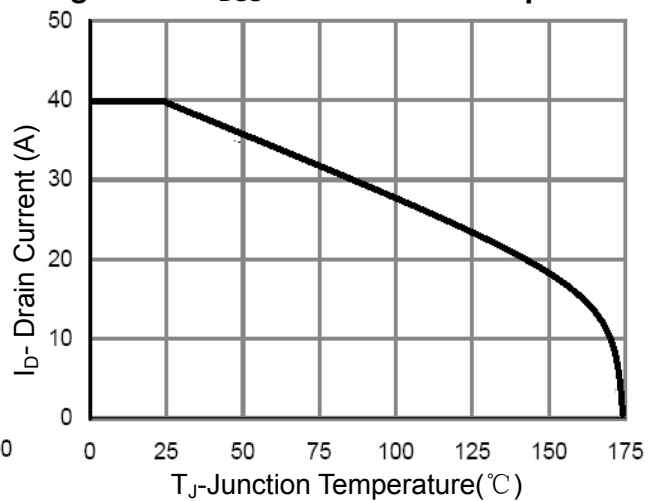


Figure 10 I_D Current Derating vs Junction Temperature

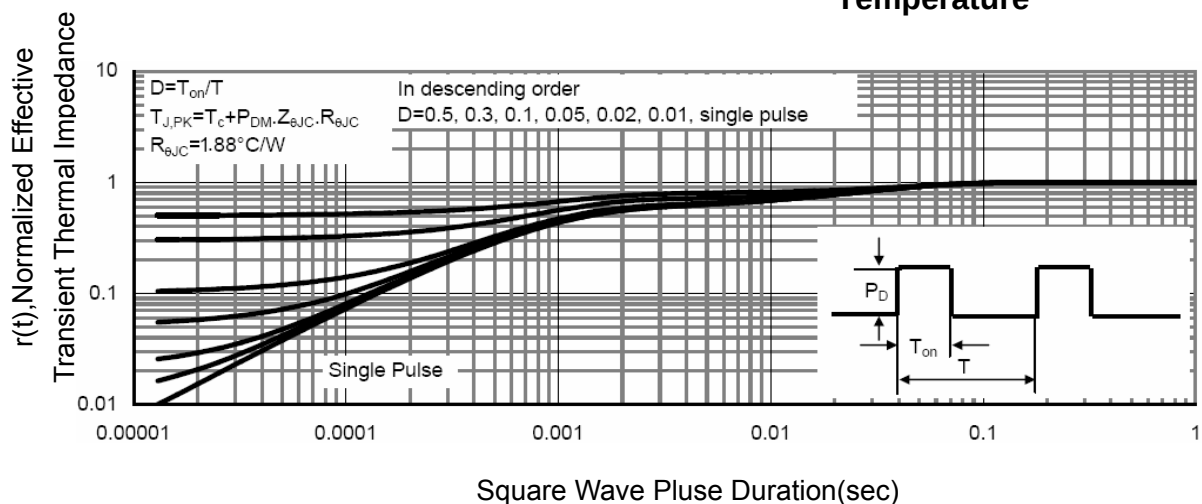
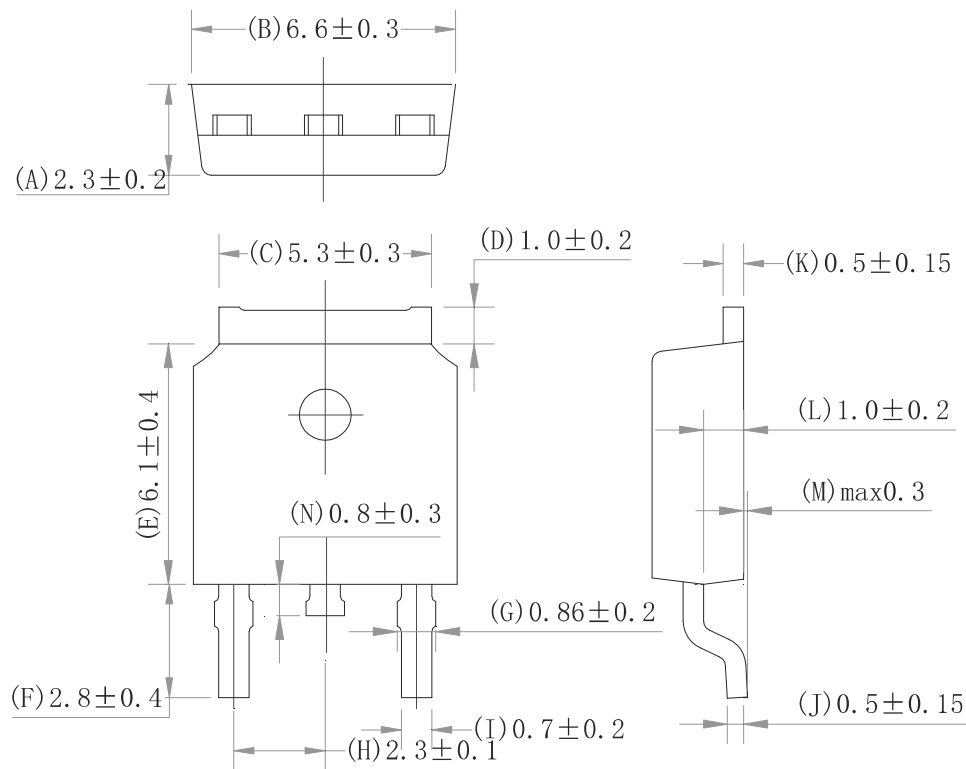


Figure 11 Normalized Maximum Transient Thermal Impedance

PACKAGE MECHANICAL



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